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Application No.	Applicant(s)
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SEARCHED				
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Class	Subclass	Date	Examiner	
716	1-18	9/30/2004	ВТ	
714	2,14-16	9/30/2004	вт	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
716	1-18	9/30/2004	вт		
716	2,14-16	9/30/2004	ВТ		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST SEARCH	9/30/2004	вт
IEEE	9/30/2004	ВТ